

ABSTRACT OF THE DISCLOSURE

The invention includes an integrated circuit (IC). The IC ~~may include~~ an internal test bus (ITB). The IC ~~may~~ also include a number of deskew clusters connected to the ITB.

- 5 The deskew clusters each include a deskew controller. The IC
~~may~~ also include an integrated test controller (ITC)
connected to the ITB. Further, the IC ~~may~~ include a debug
unit connected to the ITC. The ITC generates a single global
control signal and the deskew controller generates a first
10 local command signal.